EE 330
Homework Assignment 4
Spring 2024 (Due Friday Feb 9 at noon)

Note: Key characteristics of two different processes are appended at the end of this assignment.

## Problem 13.1 of Weste and Harris (WH)

## Problem 23.2 of WH

Problem 3 If a transistor of length 7 nm and width 14 nm has a gate oxide thickness of $25 \mathrm{~A}^{\circ}$, how many silicon dioxide molecules will be needed for the gate oxide?

Problem 4 A section of global interconnect (See Fig. 3.12 of WH) is shown below where the $\mathrm{SiO}_{2}$ insulating material has been removed. If this interconnect were made of aluminum and is $1000 \mu \mathrm{~m}$ long, 20 nm wide, and 40 nm thick, what would be the resistance of the interconnect?


## Problem 53.5 of WH

Problem 6 How many 12 inch wafers can be obtained from a 2 m silicon pull? Assume the kerf width when a wire saw is used is to cut the wafers is $150 \mu \mathrm{~m}$. In solving this problem, state and use a typical value for the wafer thickness.

Problem $7 \quad$ A first-order RC filter is shown. The 3-dB band edge of this filter is given by $\omega_{3 d B}=\frac{1}{R C}$. Assume Poly 1 with a silicide block is used to make the resistor and the capacitor is a Poly Insulator Substrate capacitor. This filter is to be fabricated in the TSMC $0.18 \mu$ CMOS process that is characterized by the parameters attached to this assignment.
a) Design this circuit and estimate the area required to implement this filter in your design if the 3 dB band edge is to be located at 1 K Hz and the capacitor value is 8 pF .
b) If the resistor is too big or the capacitor is too big, the area required to realize this filter becomes very large. Determine the value of R and C that will minimize the total area and compare the area required for the "minimal area" design with that you required in part a). Use a serpentine layout for the resistor.


Problem 8 Consider the layout of a transistor shown below where red is polysilicon and green is n -active. Rulers with dimensions in $\mu \mathrm{m}$ are shown.

a) What is the drawn length and width of the transistor?
b) Assume positive photoresist is used pattern the polysilicon region to protect it during the polysilicon etch. If the photoresist is under-exposed so that the edges move by $0.1 \mu \mathrm{~m}$ from the desired location and the photoresist development is perfect, and the polysilicon is under-etched so that the edges move by $0.1 \mu \mathrm{~m}$, what will be the actual length and width of the transistor? (neglect any lateral diffusion that may occur)
c) Repeat part b) if negative photoresist is used.

Problem 9 An aluminum interconnect $250 \mu \mathrm{~m}$ long and $2 \mu \mathrm{~m}$ wide has a measured resistance of $25 \Omega$. Determine the thickness of the aluminum interconnect and the sheet resistance. If a copper interconnect has the same thickness and the same width
as the aluminum interconnect, how long would it be if it also had the same resistance?

Problem 10 Thermal oxide growth of field oxide causes the wafer surface to become somewhat nonplanar. If $5000 \AA$ of field oxide is thermally grown, what is the difference in the thickness of the wafer between regions where field oxide is present and where it is absent. In solving this problem, state and use a typical value for the wafer thickness.

## Measured Parameters for an ON $0.5 \mu \mathrm{~m}$ CMOS Process

| MINIMUM Vth | 3.0/0.6 |  | 0.78 |  |  | 93 vo | volts |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SHORT | 20.0/0.6 |  |  |  |  |  |  |  |  |
| Idss |  |  | 439 |  | -238 |  | uA/um |  |  |
| Vth |  |  | 0.69 |  |  | 90 vo | volts |  |  |
| Vpt |  |  | 10.0 |  | -10 |  | volts |  |  |
| WIDE |  | .0/0.6 |  |  |  |  |  |  |  |
| Ids 0 |  |  | $<2$. |  | $<2$ | 5 pA | um |  |  |
| LARGE |  | / 50 |  |  |  |  |  |  |  |
| Vth |  |  |  |  |  | 95 vo | ts |  |  |
| Vjbkd |  |  | 11. |  | -11 | 7 vo | ts |  |  |
| Ijlk |  |  | <50. |  | $<50$ | 0 pA |  |  |  |
| Gamma |  |  | 0. |  |  | 58 V ${ }^{\text { }}$ | . 5 |  |  |
| $K^{\prime}$ (Uo*Cox/2) |  |  | 56. |  | -18 | 4 uA | $\mathrm{V}^{\wedge} 2$ |  |  |
| Low-field Mobility |  |  | 474. |  | 153 | 46 cm | 2/V*s |  |  |
| COMMENTS: XL_AMI_C5F |  |  |  |  |  |  |  |  |  |
| FOX TRANSISTORS Vth | GATEPoly |  | $\begin{gathered} \mathrm{N}+\text { ACTIVE } \\ >15.0 \end{gathered}$ |  | $\begin{gathered} \text { P+ACTIVE } \\ <-15.0 \end{gathered}$ |  | UNITS <br> volts |  |  |
|  |  |  |  |  |  |  |  |
| PROCESS PARAMETERS | N+ACTV | P+ACTV |  |  | POLY | PLY | Y2_HR | POLY2 | MTL1 | MTL2 | UNITS |
| Sheet Resistance | 82.7 | 103.2 | 21.7 |  | 84 | 39.7 | 0.09 | 0.09 | ohms/sq |
| Contact Resistance | 56.2 | 118.4 | 14.6 |  |  | 24.0 |  | 0.78 | ohms |
| Gate Oxide Thickness | 144 |  |  |  |  |  |  |  | gstrom |
| PROCESS PARAMETERS |  | MTL3 | $N \backslash P L Y$ |  | N_WE | L UN | TS |  |  |
| Sheet Resistance |  | 0.05 | 824 |  |  | O | ns/sq |  |  |
| Contact Resistance |  | 0.78 |  |  |  |  |  |  |  |

COMMENTS: $N \backslash P O L Y$ is $N$-well under polysilicon.

| CAPACITANCE PARAMETERS | N+ACTV | P+ACTV | POLY | POLY2 | M1 | M2 | M3 | N_WELL | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Area (substrate) | 429 | 721 | 82 |  | 32 | 17 | 10 | 40 | aF/um^2 |
| Area (N+active) |  |  | 2401 |  | 36 | 16 | 12 |  | aF/um^2 |
| Area (P+active) |  |  | 2308 |  |  |  |  |  | aF/um^2 |
| Area (poly) |  |  |  | 864 | 61 | 17 | 9 |  | $\mathrm{aF} / \mathrm{um}^{\wedge} 2$ |
| Area (poly2) |  |  |  |  | 53 |  |  |  | aF/um^2 |
| Area (metal1) |  |  |  |  |  | 34 | 13 |  | aF/um^2 |
| Area (metal2) |  |  |  |  |  |  | 32 |  | $a \mathrm{~F} / \mathrm{um}^{\wedge} 2$ |
| Fringe (substrate) | 311 | 256 |  |  | 74 | 58 | 39 |  | aF/um |
| Fringe (poly) |  |  |  |  | 53 | 40 | 28 |  | aF/um |
| Fringe (metall) |  |  |  |  |  | 55 | 32 |  | aF/um |
| Fringe (metal2) |  |  |  |  |  |  | 48 |  | aF/um |
| Overlap (N+active) |  |  | 206 |  |  |  |  |  | aF/um |
| Overlap (P+active) |  |  | 278 |  |  |  |  |  | aF/um |

## MOSIS WAFER ACCEPTANCE TESTS for TSMC $0.18 \mu \mathrm{~m}$ CMOS Process



## CAPACITANCE PARAMETERS

|  | $\mathrm{N}+$ | P+ | POLY | M1 | M2 | M3 | M4 | M5 | M6 | R_W | D_N_W | M5P | N_W | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Area (substrate) | 998 | 1152 | 103 | 39 | 19 | 13 | 9 | 8 | 3 |  | $\overline{129}$ |  | 127 | aF/um^2 |
| Area (N+active) |  |  | 8566 | 54 | 21 | 14 | 11 | 10 | 9 |  |  |  |  | aF/um^2 |
| Area (P+active) |  |  | 8324 |  |  |  |  |  |  |  |  |  |  | aF/um^2 |
| Area (poly) |  |  |  | 64 | 18 | 10 | 7 | 6 | 5 |  |  |  |  | aF/um^2 |
| Area (metal1) |  |  |  |  | 44 | 16 | 10 | 7 | 5 |  |  |  |  | aF/um^2 |
| Area (metal2) |  |  |  |  |  | 38 | 15 | 9 | 7 |  |  |  |  | aF/um^2 |
| Area (metal3) |  |  |  |  |  |  | 40 | 15 | 9 |  |  |  |  | aF/um^2 |
| Area (metal4) |  |  |  |  |  |  |  | 37 | 14 |  |  |  |  | aF/um^2 |
| Area (metal5) |  |  |  |  |  |  |  |  | 36 |  |  | 1003 |  | aF/um^2 |
| Area ( r well) | 987 |  |  |  |  |  |  |  |  |  |  |  |  | aF/um^2 |
| Area (d well) |  |  |  |  |  |  |  |  |  | 574 |  |  |  | $a F / u m{ }^{\wedge} 2$ |
| Area (no well) | 139 |  |  |  |  |  |  |  |  |  |  |  |  | $a F / u m{ }^{\wedge} 2$ |
| Fringe (substrate) | 244 | 201 |  | 18 | 61 | 55 | 43 | 25 |  |  |  |  |  | aF/um |
| Fringe (poly) |  |  |  | 69 | 39 | 29 | 24 | 21 | 19 |  |  |  |  | aF/um |
| Fringe (metal1) |  |  |  |  | 61 | 35 |  | 23 | 21 |  |  |  |  | aF/um |
| Fringe (metal2) |  |  |  |  |  | 54 | 37 | 27 | 24 |  |  |  |  | aF/um |
| Fringe (metal3) |  |  |  |  |  |  | 56 | 34 | 31 |  |  |  |  | aF/um |
| Fringe (metal4) |  |  |  |  |  |  |  | 58 | 40 |  |  |  |  | aF/um |
| Fringe (metal5) |  |  |  |  |  |  |  |  | 61 |  |  |  |  | aF/um |
| Overlap (P+active) |  |  | 652 |  |  |  |  |  |  |  |  |  |  | aF/um |


| CIRCUIT PARAMETERS |  |  | UNITS |
| :--- | :---: | :---: | :--- |
| Inverters | K |  |  |
| Vinv | 1.0 | 0.74 | volts |
| Vinv | 1.5 | 0.78 | volts |
| Vol $(100 \mathrm{uA})$ | 2.0 | 0.08 | volts |
| Voh $(100 \mathrm{uA})$ | 2.0 | 1.63 | volts |
| Vinv | 2.0 | 0.82 | volts |
| Gain | 2.0 | -23.33 |  |
| Ring Oscillator Freq. |  |  |  |
| D1024_THK (31-stg,3.3V) | 338.22 | MHz |  |
| DIV1024 (31-stg,1.8V) | 402.84 | MHz |  |
| Ring Oscillator Power |  |  |  |
| D1024_THK (31-stg,3.3V) | 0.07 | uW/MHz/gate |  |
| DIV1024 (31-stg,1.8V) | 0.02 | uW/MHz/gate |  |

COMMENTS: DEEP_SUBMICRON


| .MODEL CMOSP PMOS ( |  |  |  | LEVEL | $=49$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| +VERSION | $=3.1$ | TNOM | $=27$ | TOX | $=4 \mathrm{E}-9$ |
| +XJ | $=1 \mathrm{E}-7$ | NCH | $=4.1589 \mathrm{E} 17$ | VTH0 | $=-0.3708038$ |
| +K1 | $=0.5895473$ | K2 | $=0.0235946$ | K3 | $=0$ |
| +K3B | $=13.8642028$ | W0 | $=1 \mathrm{E}-6$ | NLX | $=1.517201 \mathrm{E}-7$ |
| +DVT0W | $=0$ | DVT1W | $=0$ | DVT2W | $=0$ |
| +DVT0 | $=0.7885088$ | DVT1 | $=0.2564577$ | DVT2 | $=0.1$ |
| +U0 | $=103.0478426$ | UA | $=1.049312 \mathrm{E}-9$ | UB | $=2.545758 \mathrm{E}-21$ |
| +UC | $=-1 \mathrm{E}-10$ | VSAT | $=1.645114 \mathrm{E} 5$ | A0 | $=1.627879$ |
| +AGS | $=0.3295499$ | B0 | $=5.207699 \mathrm{E}-7$ | B1 | $=1.370868 \mathrm{E}-6$ |
| +KETA | $=0.0296157$ | A1 | $=0.4449009$ | A2 | $=0.3$ |
| +RDSW | $=306.5789827$ | PRWG | $=0.5$ | PRWB | $=0.5$ |
| +WR | $=1$ | WINT | $=0$ | LINT | $=2.761033 \mathrm{E}-8$ |
| +XL | $=0$ | XW | $=-1 \mathrm{E}-8$ | DWG | $=-2.433889 \mathrm{E}-8$ |
| +DWB | $=-9.34648 \mathrm{E}-11$ | VOFF | $=-0.0867009$ | NFACTOR | $=2$ |
| +CIT | $=0$ | CDSC | $=2.4 \mathrm{E}-4$ | CDSCD | $=0$ |
| +CDSCB | $=0$ | ETA0 | $=1.018318 \mathrm{E}-3$ | ETAB | $=-3.206319 \mathrm{E}-4$ |
| +DSUB | $=1.094521 \mathrm{E}-3$ | PCLM | $=1.3281073$ | PDIBLC1 | $=2.394169 \mathrm{E}-3$ |
| +PDIBLC2 | $=-3.255915 \mathrm{E}-6$ | PDIBLCB | $=-1 \mathrm{E}-3$ | DROUT | $=0$ |
| +PSCBE1 | $=4.881933 \mathrm{E} 10$ | PSCBE2 | $=5 \mathrm{E}-10$ | PVAG | $=2.0932623$ |
| + DELTA | $=0.01$ | RSH | $=7.5$ | MOBMOD | $=1$ |
| +PRT | $=0$ | UTE | $=-1.5$ | KT1 | $=-0.11$ |
| +KT1L | $=0$ | KT2 | $=0.022$ | UA1 | $=4.31 \mathrm{E}-9$ |
| +UB1 | $=-7.61 \mathrm{E}-18$ | UC1 | $=-5.6 \mathrm{E}-11$ | AT | $=3.3 \mathrm{E} 4$ |
| +WL | $=0$ | WLN | $=1$ | WW | $=0$ |
| +WWN | $=1$ | WWL | $=0$ | LL | $=0$ |
| +LLN | $=1$ | LW | $=0$ | LWN | $=1$ |
| +LWL | $=0$ | CAPMOD | $=2$ | XPART | $=0.5$ |
| +CGDO | $=6.52 \mathrm{E}-10$ | CGSO | $=6.52 \mathrm{E}-10$ | CGBO | $=1 \mathrm{E}-12$ |
| +CJ | $=1.157423 \mathrm{E}-3$ | PB | $=0.8444261$ | MJ | $=0.4063933$ |
| +CJSW | $=1.902456 \mathrm{E}-10$ | PBSW | $=0.8$ | MJSW | $=0.3550788$ |
| +CJSWG | $=4.22 \mathrm{E}-10$ | PBSWG | $=0.8$ | MJSWG | $=0.3550788$ |
| +CF | $=0$ | PVTH0 | $=1.4398 \mathrm{E}-3$ | PRDSW | $=0.5073407$ |
| +PK2 | $=2.190431 \mathrm{E}-3$ | WKETA | $=0.0442978$ | LKETA | $=-2.936093 \mathrm{E}-3$ |
| +PU0 | $=-0.9769623$ | PUA | $=-4.34529 \mathrm{E}-11$ | PUB | $=1 \mathrm{E}-21$ |
| +PVSAT | $=-50$ | PETA0 | $=1.002762 \mathrm{E}-4$ | PKETA | $=-6.740436 \mathrm{E}-3$ |

